

Form PTO-1449  
(REV. 1/06)US Dept. of Commerce  
PATENT & TRADEMARK OFFICEATTY DOCKET NO.  
129429APPLICATION NO.  
10/593,802

## INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT(S)  
Hideaki HARAFILING DATE  
September 21, 2006GROUP  
2882

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